

PRODUCT EVALUATION



Date: January, 2008

**PRODUCT EVALUATION REPORT FOR
Series:770
TIN WHISKER TEST**

**Tin Whisker Report
Series: 770**

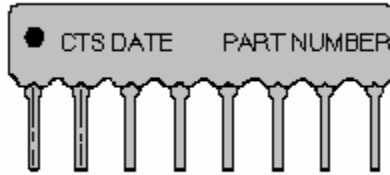


Figure 1. Package Style

Single-In-Line resistor network testing performed per conditions as outlined in Table 1.

Termination plating is Sn/3.0Ag/0.5Cu.

Whisker length criteria is $\leq 50 \mu\text{m}$.

Sample Size: n= 5.

Test	Test Condition	Maximum Whisker Length
Temperature Cycling	-40°C to +125°C, 500 Cycles, 30 minutes at each extreme	0 μm - SEM measurements – No Whiskers Detected
High Temperature / High Humidity Exposure	+85°C / 85% RH, 500 Hours	0 μm - SEM measurements – No Whiskers Detected

Table 1. Test Conditions and Results

Temperature Cycle:

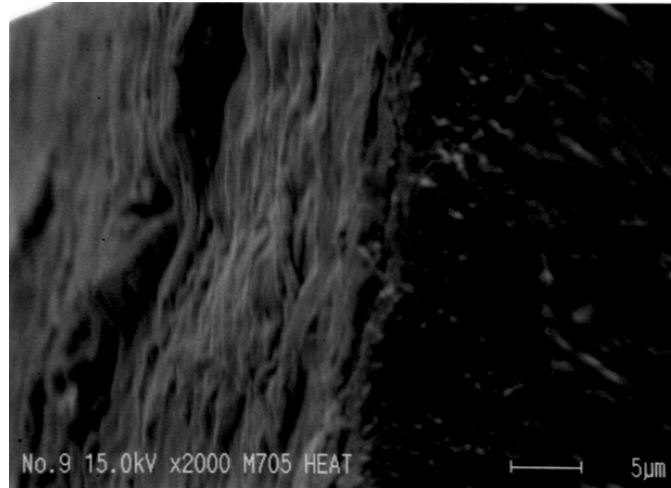


Figure 2. Terminal Surface SEM (x2000) Photograph

High Temperature and High Humidity Exposure:

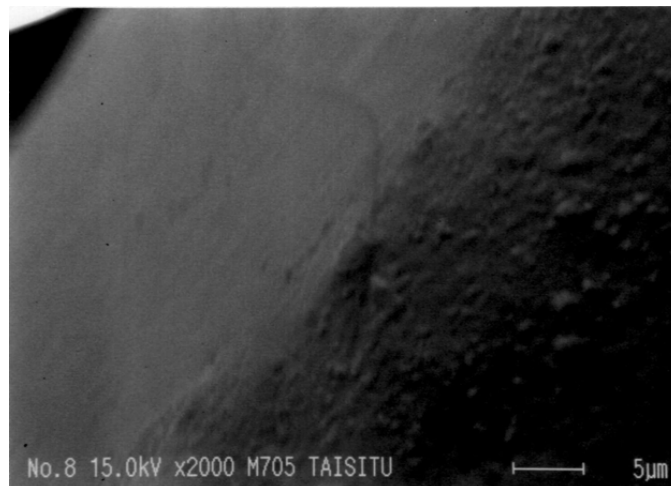


Figure 3. Terminal Surface SEM (x2000) Photograph

This test report data is for reference only, based on the conditions and samples used during the evaluation and is not guaranteed for all environments or all conditions.